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FAIRCHILD SEMICONDUCTOR™

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74ACT533

Octal Transparent Latch with 3-STATE Outputs

General Description

The ACT533 consists of eight latches with 3-STATE outputs for bus organized system applications. The flip-flops appear transparent to the data when Latch Enable (LE) is HIGH. When LE is low, the data satisfying the input timing requirements is latched. Data appears on the bus when the Output Enable (OE) is LOW. When OE is HIGH, the bus output is in the high impedance state.

Features

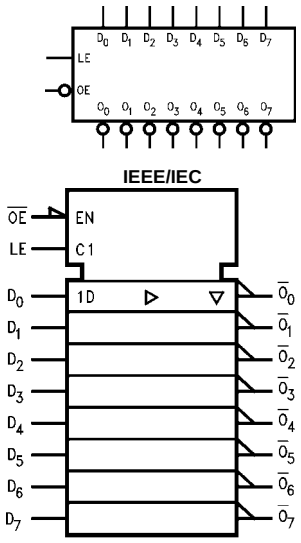
- I_{CC} and I_{OZ} reduced by 50%
- Eight latches in a single package
- 3-STATE outputs drive bus lines or buffer memory address registers
- Outputs source/sink 24 mA
- Inverted version of the ACT373
- TTL-compatible inputs

Ordering Code:

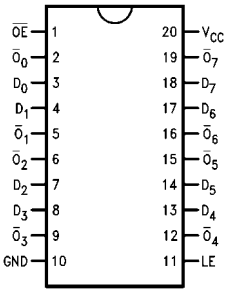
Order Number	Package Number	Package Description
74ACT533SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACT533MTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
74ACT533PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code

Logic Symbols



Connection Diagram



Pin Descriptions

Pin Names	Description
D_0–D_7	Data Inputs
LE	Latch Enable Input
$\overline{OE}$	Output Enable Input
$\overline{O}_0$–$\overline{O}_7$	3-STATE Latch Outputs

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Functional Description

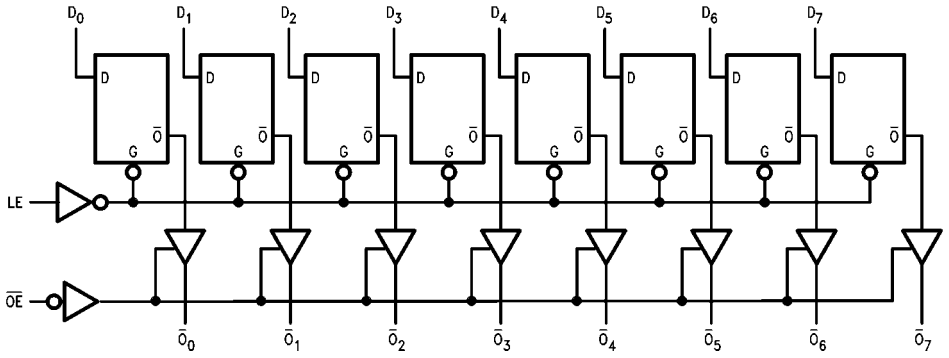
The ACT533 contains eight D-type latches with 3-STATE standard outputs. When the Latch Enable (LE) input is HIGH, data on the D_n inputs enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its D input changes. When LE is LOW, the latches store the information that was present on the D inputs at setup time preceding the HIGH-to-LOW transition of LE. The 3-STATE standard outputs are controlled by the Output Enable ($\overline{OE}$) input. When $\overline{OE}$ is LOW, the standard outputs are in the 2-state mode. When $\overline{OE}$ is HIGH, the standard outputs are in the high impedance mode but this does not interfere with entering new data into the latches.

Truth Table

Inputs			Outputs
LE	**$\overline{OE}$**	**D_n**	**$\overline{O}_n$**
X	H	X	Z
H	L	L	H
H	L	H	L
L	L	X	$\overline{O}_0$

H = HIGH Voltage Level
L = LOW Voltage Level
Z = High Impedance
X = Immaterial
$\overline{O}_0$ = Previous $\overline{O}_0$ before HIGH-to-LOW transition of Latch Enable

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

Supply Voltage (V_{CC})	− 0.5V to + 7.0V
DC Input Diode Current (I_{IK})	
V_I = − 0.5V	− 20 mA
V_I = V_{CC} + 0.5V	+ 20 mA
DC Input Voltage (V_I)	−0.5V to V_{CC} + 0.5V
DC Output Diode Current (I_{OK})	
V_O = − 0.5V	− 20 mA
V_O = V_{CC} + 0.5V	+ 20 mA
DC Output Voltage (V_O)	− 0.5V to V_{CC} + 0.5V
DC Output Source or Sink Current (I_O)	± 50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	± 50 mA
Storage Temperature (T_{STG})	− 65°C to + 150°C
DC Latchup Source or Sink Current	± 300 mA
Junction Temperature (T_J)	
PDIP	140°C

Recommended Operating Conditions

Supply Voltage (V_{CC})	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	−40°C to +85°C
Minimum Input Edge Rate ΔV/Δt	
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 4.5V, 5.5V	125 mV/ns

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. Fairchild does not recommend operation of FACT™ circuits outside databook specifications.

DC Electrical Characteristics

Symbol	Parameter	V_{CC} (V)	T_A = +25°C Typ	T_A = −40°C to +85°C Guaranteed Limits		Units	Conditions
V_{IH}	Minimum HIGH Level Input Voltage	4.5	1.5	2.0	2.0	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
		5.5	1.5	2.0	2.0		
V_{IL}	Maximum LOW Level Input Voltage	4.5	1.5	0.8	0.8	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
		5.5	1.5	0.8	0.8		
V_{OH}	Minimum HIGH Level Output Voltage	4.5	4.49	4.4	4.4	V	I_{OUT} = −50 μA
		5.5	5.49	5.4	5.4		
							V_{IN} = V_{IL} or V_{IH}
		4.5		3.86	3.76	V	I_{OH} = −24 mA
		5.5		4.86	4.76		I_{OH} = −24 mA (Note 2)
V_{OL}	Maximum LOW Level Output Voltage	4.5	0.001	0.1	0.1	V	I_{OUT} = 50 μA
		5.5	0.001	0.1	0.1		
							V_{IN} = V_{IL} or V_{IH}
		4.5		0.36	0.44	V	I_{OL} = 24 mA
		5.5		0.36	0.44		I_{OL} = 24 mA (Note 2)
I_{IN}	Maximum Input Leakage Current	5.5		±0.1	±1.0	μA	V_I = V_{CC}, GND
I_{OZ}	Maximum 3-STATE Leakage Current	5.5		±0.25	±2.5	μA	V_I = V_{IL}, V_{IH} V_O = V_{CC}, GND
I_{CCT}	Maximum I_{CC}/Input	5.5	0.6		1.5	mA	V_I = V_{CC} − 2.1V
I_{OLD}	Minimum Dynamic	5.5			75	mA	V_{OLD} = 1.65V Max
I_{OHD}	Output Current (Note 3)	5.5			−75	mA	V_{OHD} = 3.85V Min
I_{CC}	Maximum Quiescent Supply Current	5.5		4.0	40.0	μA	V_{IN} = V_{CC} or GND

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

AC Electrical Characteristics

Symbol	Parameter	V_{CC} (V) (Note 4)	$T_A = +25°C$, $C_L = 50$ pF			$T_A = -40°C$ to $+85°C$, $C_L = 50$ pF		Units
			Min	Typ	Max	Min	Max	
t_{PHL} t_{PLH}	Propagation Delay D_n to O_n	5.0	2.0	6.0	8.0	2.0	8.5	ns
t_{PHL} t_{PLH}	Propagation Delay LE to O_n	5.0	2.5	7.0	9.0	2.5	9.5	ns
t_{PZL}, t_{PZH}	Output Enable Time	5.0	2.0	7.0	9.0	2.0	9.5	ns
t_{PHZ}, t_{PLZ}	Output Disable Time	5.0	1.0	8.0	10.0	1.0	10.5	ns

Note 4: Voltage Range 5.0 is 5.0V ± 0.5V.

AC Operating Requirements

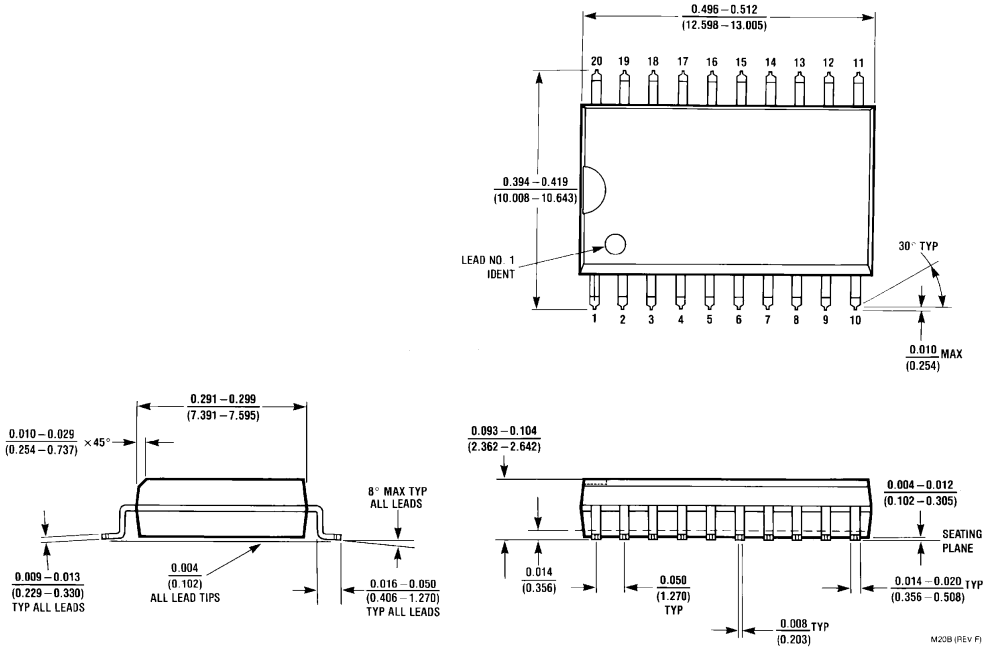
Symbol	Parameter	V_{CC} (V) (Note 5)	$T_A = +25°C$, $C_L = 50$ pF		$T_A = -40°C$ to $+85°C$, $C_L = 50$ pF	Units
			Typ	Guaranteed Minimum		
t_S	Setup Time, HIGH or LOW D_n to LE	5.0	0	3.0	3.0	ns
t_H	Hold Time, HIGH or LOW D_n to LE	5.0	0	1.5	1.5	ns
t_W	LE Pulse Width, HIGH	5.0	2.0	4.0	4.0	ns

Note 5: Voltage Range 5.0 is 5.0V ± 0.5V.

Capacitance

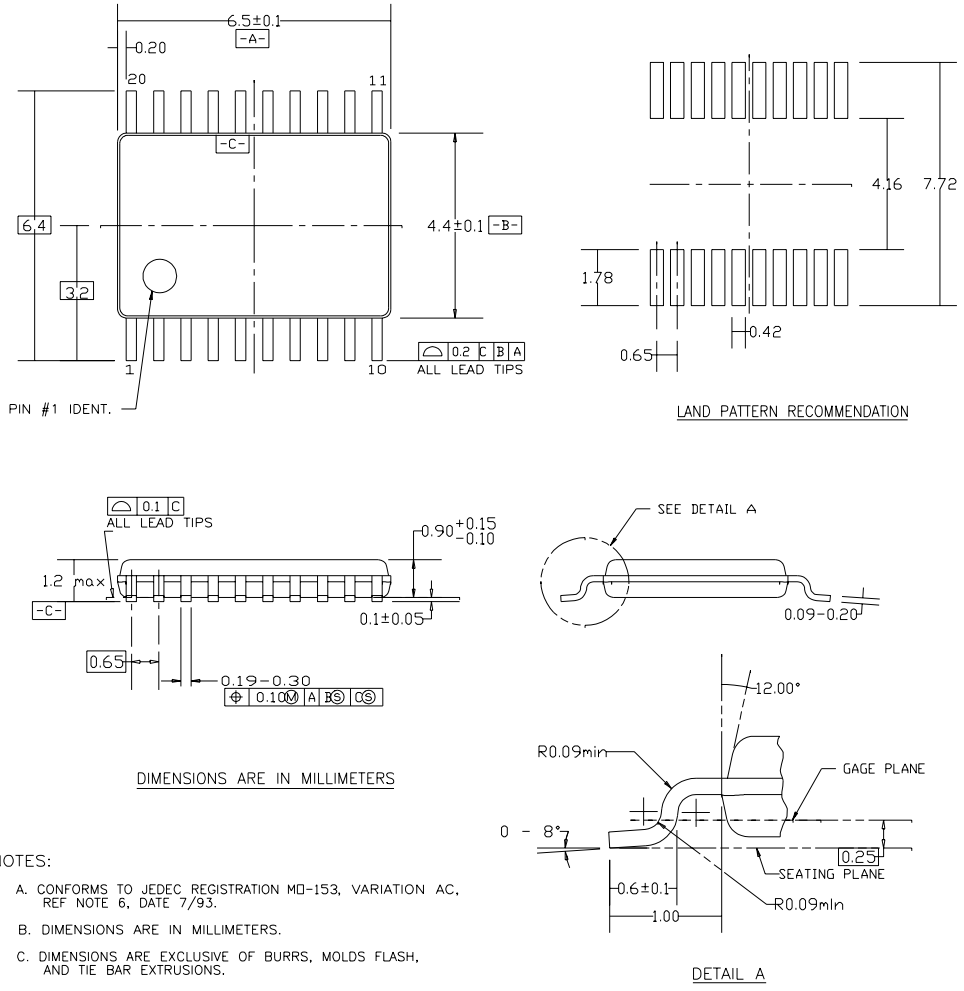
Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	V_{CC} = OPEN
C_{PD}	Power Dissipation Capacitance	40	pF	V_{CC} = 5.0V

Physical Dimensions inches (millimeters) unless otherwise noted



20-Lead Small Outline Integrated Circuit, JEDEC MS-013, 0.300" Wide Body
Package Number M20B

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



NOTES:

A. CONFORMS TO JEDEC REGISTRATION MO-153, VARIATION AC, REF NOTE 6, DATE 7/93.

B. DIMENSIONS ARE IN MILLIMETERS.

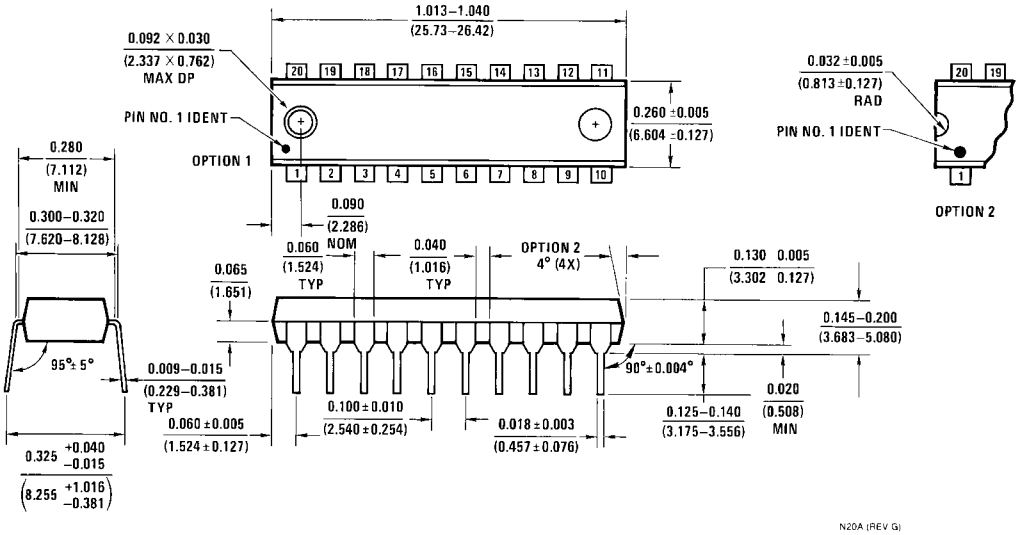
C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLDS FLASH, AND TIE BAR EXTRUSIONS.

D. DIMENSIONS AND TOLERANCES PER ANSI Y14.5M, 1982.

MTC20REVD1

20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
Package Number MTC20

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



20-Lead Plastic Dual-In-Line Package, JEDEC MS-001, 0.300" Wide
Package Number N20A

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